FORM PTO-1449 (MODIFIED)					ATTORNEY DOCKET NO.			SERIAL NO.			
LIST OF PATENTS AND PUBLICATIONS					WJT003-0043 (SP03-172)			70/733,792			
FOR APPLICANTS INFORMATION					APPLICANT						
DISCLOSURE STATEMENT					Dishard NV Channel						
					FILING DATE			GROUP: TBA 2877			
REFERE	NCE D	ESIGNATION		U.	S. PATENT DOCUMENTS						
Examiner Initial (Document Number	Date		Name	Clas	ss	Sub- Class	Filing Date if Approp.		
811	AA	5,521,705	05-28-96		Rudolf Oldenbourg et al.	356		368			
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	AD										
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	AP										
	AQ										
		OTHER ART (ncluding	۸ı	uthor Title Date Pertinent l	Pages	etc `	`			
GN	AR	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) R. Oldenbourg et al., "New polarized light microscope with precision universal compensator", Journal of Microscopy, Vol. 180, Pt. 2, November 1995, pg. 140-147									
BN,	AS	B. Wang et al., "A new instrument for measuring both the magnitude and angle of low level linear birefringence", Review of Scientific Instruments, Vol. 70, No. 10, October 1999, pgs. 3847-3854									
aw	AT	R. Oldenbourg, "A new view on polarization microscopy", Nature, Vol. 381, June 27, 1996, pgs. 811-812									
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EXAMINE	ER:	Sargwon			DATE	CONSI	DE	RED:	/27/	KS	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.